

**Search Notes (continued)**

Application/Control No.

10/624,610

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

KANAYA ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
updated	updated	2/10/2005	<i>SWH</i> SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
347	29,35	2/10/2005	<i>SWH</i> SWH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search (see attached)	2/10/2005	<i>SWH</i> SWH